The size of the "process" indicates the minimum possible channel length. Magnitude of the electron charge in the channel [Q]:

$$|Q| = C_{OX}(WL)v_{OV}$$
  
 $C_{OX}$  is the oxide capacitance, [F/m<sup>2</sup>]

$$C_{OX} = \frac{\epsilon_{OX}}{t_{OX}}$$

 $\epsilon_{OX}$  is the permittivity of the SiO<sub>2</sub>.  $t_{OX}$  is the oxide thickness. For  $C_{OX}$  per micron squared, use  $C = C_{OX}WL$  [fF]

$$i_{D} = \left[ (\mu_{n} C_{OX}) \left( \frac{W}{L} \right) (v_{GS} - V_{t}) \right] v_{DS}$$

$$i_{D} = \left[ g_{DS} \right] v_{DS}$$

$$k'_{n} = \mu_{n} C_{OX}$$

$$k_{n} = k'_{n} (W/L)$$

 $k_n^{'}$  is process transconductance paramter.  $k_n$  is device transconductance

## paramter.

When  $V_{DS}$  is small, the MOSFET behaves as a linear resistance  $r_{DS}$  whose value is controlled by the gate voltage  $v_{GS}$ .

$$r_{DS} = \frac{1}{g_{DS}}$$

Triode vs Saturation Triode  $(v_{DS} \leq V_{OV})$ 

$$\begin{split} i_D &= k_n^{'} \left(\frac{W}{L}\right) \left(V_{OV} - \frac{1}{2}v_{DS}\right) v_{DS} \\ i_D &= k_n^{'} \left(\frac{W}{L}\right) \left[(v_{GS} - V_t)v_{DS} - \frac{1}{2}v_{DS}^2\right] \end{split}$$

Saturation  $(v_{DS} \ge V_{OV})$ 

$$i_D = \frac{1}{2} k_n' \left(\frac{W}{L}\right) V_{OV}^2$$

 $k_n = k'_n$ , so

$$i_D = \frac{1}{2} k_n V_{OV}^2$$

Or,

$$i_D = \frac{1}{2}k_n(V_{GS} - V_{th})^2$$

Constant  $V_{OV}$  can be replaced by variable

PMOS transistors operate similarly but the polarity is reversed, so  $v_{GS}$  must be negative and larger than a negative  $v_{tp}$ , as is  $v_{DS}$ 

If you care about channel-length modulation, then use the expression:

$$i_D = \frac{1}{2}k'_n \left(\frac{W}{L}\right)(v_{GS} - V_{th})^2(1 + \lambda v_{DS})$$

 $\begin{array}{l} v_{DS} = -\frac{1}{\lambda} \mid V_A = \frac{1}{\lambda} \mid V_A = V_A^{'}L \\ V_A \text{ (Early Voltage) has units of volts.} \\ V_A^{'} \text{ has units of volts per micron.} \\ \text{Expression for } r_o\text{:} \end{array}$ 

$$r_o = \frac{V_A}{I_D} = \frac{1}{\lambda I_D}$$

 $r_o = \frac{V_A}{I_D} = \frac{1}{\lambda I_D}$   $I_D$  is the drain current without channel-length modulation taken into account.

$$I_D = \frac{1}{2} k_n' \frac{W}{L} (V_{GS} - V_{tn})^2$$

 $I_D = \frac{1}{2}k_n'\frac{W}{L}(V_{GS} - V_{tn})^2$  For a p-Channel MOSFET, everything is backwards, here is an equation showing the voltages without negative signs, everything here is considered in terms of positive voltages or magnitudes.

voltages or magnitudes. 
$$i_{D} = \frac{1}{2}k_{p}^{'}\left(\frac{W}{L}\right)\left(v_{SG} - |V_{tp}|\right)^{2}(1 + |\lambda|v_{SD})$$
 Also,

Also,
$$i_{D} = \frac{1}{2}k_{p}^{'}\left(\frac{W}{L}\right)\left(v_{SG} - |V_{tp}|\right)^{2}\left(1 + \frac{v_{SD}}{|V_{A}|}\right)$$
Kinda useful:

$$R_D = \frac{V_{DD} - V_D}{I_D}$$

$$R_D = V_{DD} - I_D R_D$$

MOSFETs biased for linear amplification Note bias point Q. Voltages  $V_{GS}$  and  $V_{DS}$ are related at the bias point by

$$v_{DS} = V_{DD} - \frac{1}{2}k_nR_D(v_{GS} - V_t)^2$$

$$v_{GS} = V_{GS} + v_{qs}$$

 $A_v$  is expressed in terms of  $V_{OV}$  at the bias point by

$$A_v = -k_n V_{OV} R_D$$

$$A_v = -\frac{2I_D R_D}{V_{OV}} = -\frac{I_D R_D}{V_{OV}/2}$$

To prevent nonlinear distortion,  $v_{qs}$  must be sufficiently small.

$$v_{gs} \ll 2(V_{GS} - Vt)$$
$$v_{gs} \ll 2V_{OV}$$

When this condition is met, we can express  $i_D$  as:

$$i_D \simeq I_D + i_d$$

Of course, 
$$I_D = \frac{1}{2}k_nV_{OV}^2$$
  
and  $i_d = k_n(V_{GS} - V_t)v_{gs}$ 

$$g_m \equiv \frac{i_d}{v_{as}} = k_n (V_{GS} - V_t)$$

$$g_m = k_n V_{OV} = \mu_n C_{ox} \frac{W}{L} V_{OV}$$

$$g_m = k'_n(W/L)(V_{GS} - V_t) = k'_n(W/L)V_{OV}$$

$$g_m = \sqrt{2k_n'}\sqrt{W/L}\sqrt{I_D}$$

$$g_m = \frac{2I_D}{V_{GS} - V_t} = \frac{2I_D}{V_{OV}} = \sqrt{2\mu_n C_{ox} \frac{W}{L} I_D}$$

Small Signal Model 
$$r_o = \frac{|V_A|}{I_D} = \frac{1}{\lambda I_D} \mid A_v = \frac{v_{ds}}{v_{gs}} = -g_m(R_D \parallel r_o)$$

$$v_{DS} = V_{DD} - R_D i_D$$

$$v_{DS} = V_{DD} - R_D(I_D + i_d) = V_{DS} - R_D i_d$$

$$v_{DS} = -i_d R_D = -g_m v_{gs} R_D$$

$$A_v \equiv \frac{v_{ds}}{v_{gs}} = -g_m R_D$$

T Equivalent-Circuit Model  $i_d = \bar{i}_s = g_m v_{gs}$ 

Characterizing Amplifiers

$$A_{vo} \equiv \frac{v_o}{v_i} \Big|_{R_L = \infty}$$

$$A_v \equiv \frac{v_o}{v_i} = A_{vo} \frac{R_L}{R_L + R_o}$$

$$G_v \equiv \frac{v_o}{v_{\text{sig}}}$$

Basic circuit configurations  $\begin{aligned} R_{\text{in}} &= \infty \mid v_o = -(g_m v_{gs})(R_D \parallel r_o) \\ A_{vo} &= -g_m(R_D \parallel r_o) \\ A_v &= G_v = -g_m(R_D \parallel R_L \parallel r_o) \\ v_{\text{sig}} \text{ must be much smaller than } 2V_{OV} \end{aligned}$ 

$$\begin{aligned} v_{gs} &= \frac{v_i}{1+g_m R_s} \\ v_o &= -iR_D \\ i &= \frac{v_i}{1/g_m + R_s} = \left(\frac{g_m}{1+g_m R_s}\right) v_i \end{aligned}$$

Those two together make:

$$A_{vo} = \frac{v_o}{v_i} = -\frac{R_D}{1/g_m + R_s}$$
 
$$A_v = -\frac{R_D \parallel R_L}{1/g_m + R_s}$$
 
$$\overline{R_{in} = \frac{1}{g_m} \mid i = -\frac{v_i}{1/g_m} \mid v_o = -iR_D}$$
 
$$A_{vo} \equiv \frac{v_o}{v_i} = g_m R_D$$
 
$$G_v = \frac{(R_D \parallel R_L)}{R_{sig} + 1/g_m}$$

Often used as a voltage buffer so that the signal isn't attenuated at the output.  $R_{11} = \infty \mid A_{12} = 1 \mid R_{12} = 1/a$ 

$$R_{\rm in} = \infty \mid A_{vo} = 1 \mid R_o = 1/g_m$$

$$G_v = A_v = \frac{R_L}{R_L + 1/g_m}$$

Biasing amplifier circuits Fixing  $V_G$  and using  $R_s$ , use  $V_G = V_{GS} + R_s I_D$ 

Depletion-type MOSFET is the same as normal mosfet but it has a negative  $V_t$  (positive for PMOS).